Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

10. (currently amended) A high voltage semiconductor device comprising:

a semiconductor substrate, the semiconductor substrate including a

plurality of device structures thereon; and

an interconnect on the semiconductor substrate, the interconnect comprising at least one slot provided in the semiconductor substrate and a plurality of metals at least one metals within the at least one slot, wherein the plurality of metals comprises three metals, wherein the first and second metals fill the slot and the third metal provides an interconnect layer, the at least one metal being of sufficient thickness to carry a high current, wherein the at least one slot is oxidized everywhere except at the bottom of the slot where the interconnect forms a ground strap.

Please cancel claims 11 and 12.

11. (cancelled)

12. (cancelled)

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13. (currently amended) The semiconductor device of claim 12 10 wherein the plurality of metals comprises three metals, wherein the first and second metals fill the slot and the third metal provides an interconnect layer.

- 14. (original) The semiconductor device of claim 13 wherein the ground strap comprises an ideal short to ground.
- 15. (original) The semiconductor device of claim 14 wherein the ground strap provides for isolation between components.
- 16. (currently amended) A high voltage interconnect on a semiconductor substrate comprising:

at least one slot provided in the semiconductor substrate; and

at least one a plurality of metals within the slot, the at least one metal being of sufficient thickness to carry a high current, wherein the plurality of metals comprises three metals, wherein the first and second metals fill the slot and the third metal provides an interconnect layer, wherein the at least one slot is oxidized everywhere except at the bottom of the slot, and the interconnect forms a very low resistance ground strap.

Please cancel claims 17-19.

17. (cancelled)

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- 18. (cancelled)
- 19. (cancelled)
- 20. (original) The interconnect of claim 16 wherein the ground strap comprises an ideal short to ground.
- 21. (original) The interconnect of claim 16 wherein the ground strap provides for isolation between components.

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Application No.	Applicant(s)
10/034,279	HUSHER, JOHN DURBIN
Examiner	Art Unit
David Nhu	2818

	10/034,279	HUSHER, JOHN	HUSHER, JOHN DURBIN	
Notice of Allowability	Examiner	Art Unit		
	David Nhu	2818		
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS (herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED in t or other appropriate commun GHTS. This application is su	his application. If not inc lication will be mailed in	cluded due course. THIS	
1. This communication is responsive to <u>8/6/04</u> .				
2. The allowed claim(s) is/are 10,13-16,20 and 21.		•		
3. The drawings filed on <u>28 December 2001</u> are accepted by	the Examiner.			
4. Acknowledgment is made of a claim for foreign priority una All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE *MAILING DATE*	been received. been received in Application cuments have been received of this communication to file a	No in this national stage ap		
noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be subminformal PATENT APPLICATION (PTO-152) which give	ENT of this application. itted. Note the attached EXAI	MINER'S AMENDMENT		
6. CORRECTED DRAWINGS (as "replacement sheets") mus (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the deponsion of th	on's Patent Drawing Review s Amendment / Comment or in .84(c)) should be written on the he header according to 37 CFF sit of BIOLOGICAL MATE	in the Office action of e drawings in the front (no k 1.121(d). RIAL must be submitt		
attached Examiner's comment regarding REQUIREMENT	FOR THE DEPOSIT OF BIO	LOGICAL MATERIAL.	. •	
Attachment(s) 1. Notice of References Cited (PTO-892) 2. Notice of Draftperson's Patent Drawing Review (PTO-948) 3. Information Disclosure Statements (PTO-1449 or PTO/SB/O Paper No./Mail Date 4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Su Paper No./It 98), 7. ☑ Examiner's / 8. ☑ Examiner's 9. ☐ Other	ormal Patent Application mmary (PTO-413), Mail Date Amendment/Comment Statement of Reasons fo	,	
	Sa	402Pa		

Application/Control Number: 10/034,279

Art Unit: 2818

EXAMINER'S AMENDMENT

1. Applicant's election of claims 10-21 is acknowledged. Because Applicant did not distinctly and specifically point out the supposed error in the restriction requirement, the election has been treated as an election without traverse (MPEP § 818.03(a)). Applicant have the right to file a divisional application covering the subject matter of the non-elected claims 1-9.

The traversal is on the ground(s) that see the election paper. This is not found persuasive because the fields of search for method' and device claims are NOT coextensive and the determinations of patentability of method and device claims are different, that is process limitations and device limitations are given weight differently in determining the patentablitity of the claimed inventions. Also, the strategies for doing text searching of the device claims and method claims are different. Thus, separate searches are required.

The requirement is still deemed proper and is therefore made FINAL.

An examiner's amendment to the record appears below. Should the change and/or additions be unaceptable to applicant, an amendment may be filed as provided by 37 CFR
 To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in an interview with Attorney, Joseph A. Sawyer, Jr., on 9/27/04.

Cancel claims 1-9, 11-12, 17-19.

REASONS FOR ALLOWANCE

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3. Claims 10, 13-16, 20-21 are allowed.

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- 4. The following is an examiner's statement of reasons for allowance: None of the references of record teaches or suggests as cited in claims 10, 16: a plurality of metals within the slot, wherein the plurality of metals comprises three metals, wherein the first and second metals fill the slot and the third metal provides an interconnect layer, wherein the at least one slot is oxidized everywhere except at the bottom of the slot where the interconnect forms a ground strap (as cited in claim 10); an interconnect on the semiconductor substrate, the interconnect comprising at least one slot provided in the semiconductor substrate and a plurality of metals within the at least one slot, wherein the plurality of metals comprises three metals, wherein the first and second metals fill the clot and the third metal provides an interconnect layer, wherein the at least one slot is oxidized everywhere except at the bottom of the slot, and the interconnect forms a very low resistance ground strap (as cited in claim 16).
- 4. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

CONCLUSION

- 5. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure: Yamada (6,008,127): Semiconductor Device Having Etching Stopper Layer Formed by Oxidation and Method of Fabricating the same.
- 6. Any inquiry concerning this communication on earlier communications from the examiner should be directed to David Nhu, (571)272-1792. The examiner can normally be reached on Monday-Friday from 7:30 AM to 5:00 PM.

The examiner's supervisor, David Nelms can be reached on (571)272-1787.

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The fax phone number for the organization where this application or proceeding is assigned is (571)273-1792.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

David Nhu

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December 22, 2004

DAVID REFU